A JUL 10.	IN THE UNITED STATES PATENT AND TRADEMARK OFFICE	
PHADEM	IN THE UNITED STATES FATENT AND In re the application of: GOTKIS Application No: 10/810,209 Filed: March 26, 2004 For: METHOD AND APPARATUS FOR MEASUREMENT OF THIN FILMS AND)) Group Art Unit: 1765)) Examiner: Anita Karen Alanko)) Atty. Docket No: LAM2P466)) Date: July 5, 2006)
07/11/2006 CNEGA1 01 FC:1801	RESIDUES ON SEMICONDUCTOR SUBSTRATES I heret deposi Class	Kay Harlow
	Mail Stop: RCE Commissioner for Patents Alexandria, VA 22313-1450 Sir: This is a Request for Continued Examination (RCE) undidentified application.	ler 37 CFR 1.114 of the above-
	1. Submission required under 37 C.F.R. § 1.114 a.	
	b. Other 3. Fees a. Check in the amount of \$790.00 i. RCE fee required under 37 C.F.R. ii. Extension of time fee (37 C.F.R. §§ iii. Other b. The Director is hereby authorized to char overpayments, to Deposit Account No. 50-08 Date: July 5, 2006	is enclosed for: § 1.17(e); 1.136 and 1.17); and rge any fees, or credit any 305 (Order No. LAM2P466).
	Albert 8. Penilla, Esq.	

Registration No. 39,487